



Cornell University
Laboratory for Elementary-Particle Physics



Review of High Field Q-slope, Surface Measurements

Alexander Romanenko

Cornell University

Laboratory for Elementary-Particle Physics



- **Key properties of the HF Q-slope**
 - Mild baking removes completely (in EP) or improves it (in BCP)
 - Why the difference between EP and BCP after baking?
 - Air exposure has no effect on baking benefit
 - Observed distribution of losses in the high magnetic field region is not uniform – “hot” and “cold” spots
 - But – both “hot” and “cold” regions exhibit HF Q-slope, only amount of heating is different
- **Surface studies – looking for:**
 - What changes during mild baking and is preserved after air exposure?
 - Fine, large and single grain Nb BCP and EP samples
 - What is different between “hot” and “cold” regions?
 - Samples dissected from a not baked cavity with the HF Q-slope



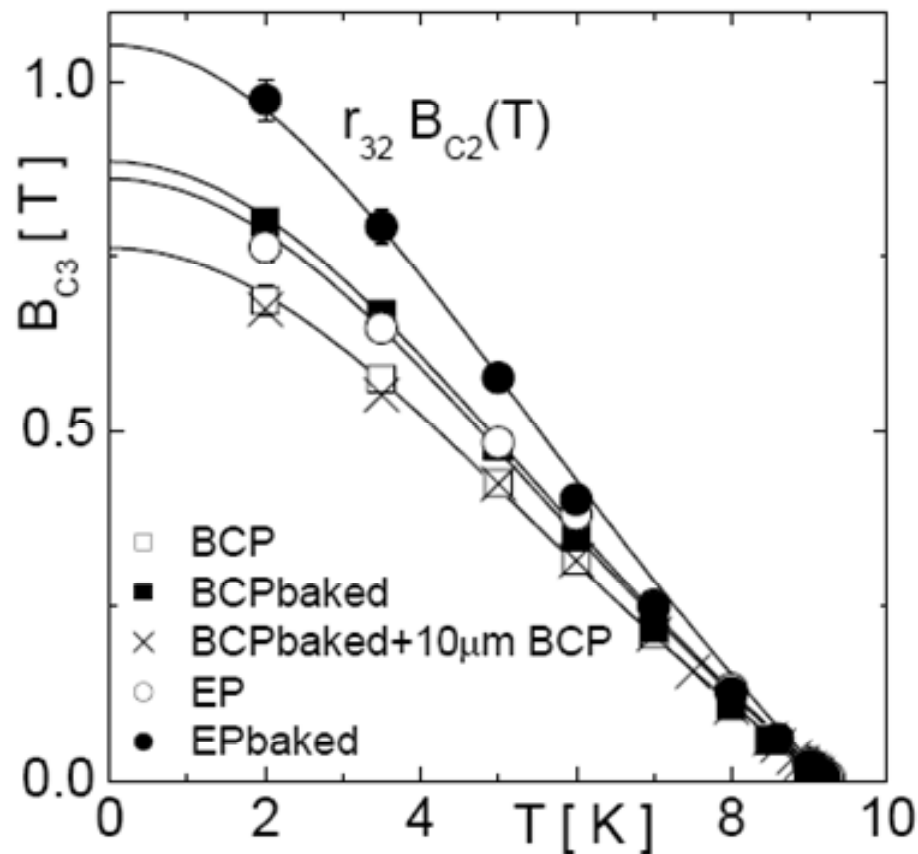
- Roughness
 - AFM, OP
- Grain Boundaries
 - Magneto-optical imaging
- Oxide structure
 - XPS
- Interstitial impurities (O, H, N, ...)
 - SIMS, ToF-SIMS, 3DAP
- Crystalline microstructure
 - EBSD



What changes during mild baking and is preserved after air exposure?



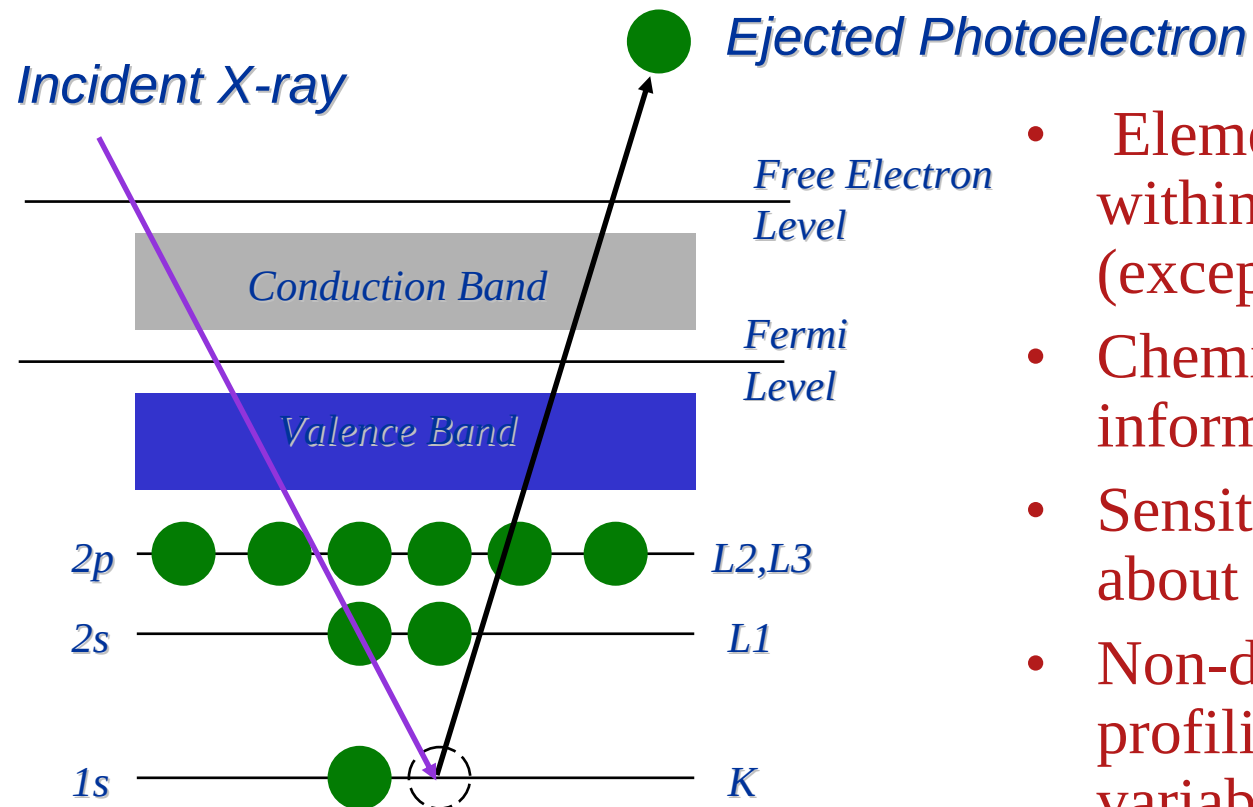
[S. Casalbuoni et al, Hamburg]



- Baking effect clearly observed
- EP superior to BCP after baking – higher B_{c3} ?



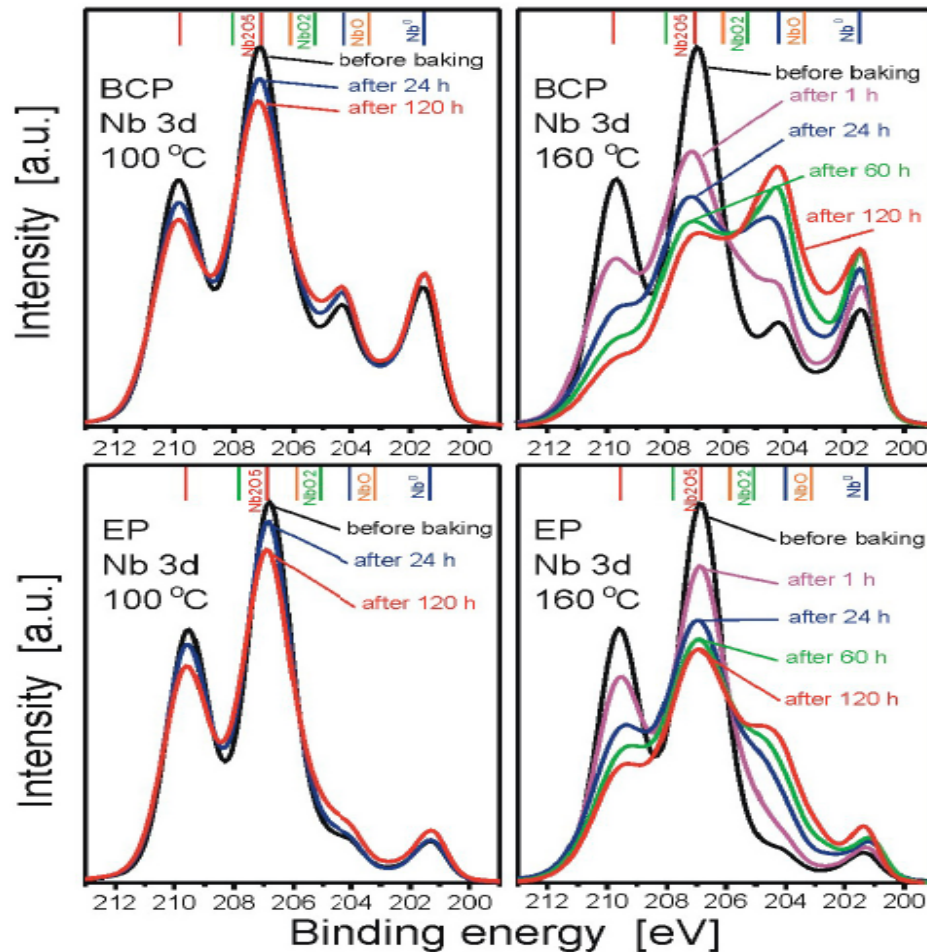
Is it oxide structure?



- Elemental composition within first few nm (except for H and He)
- Chemical state information
- Sensitivity limited to about 0.1-1 at. %
- Non-destructive depth profiling possible with variable X-ray energy or angle-resolved XPS
- But - mostly oxide signal



Oxide structure (XPS)

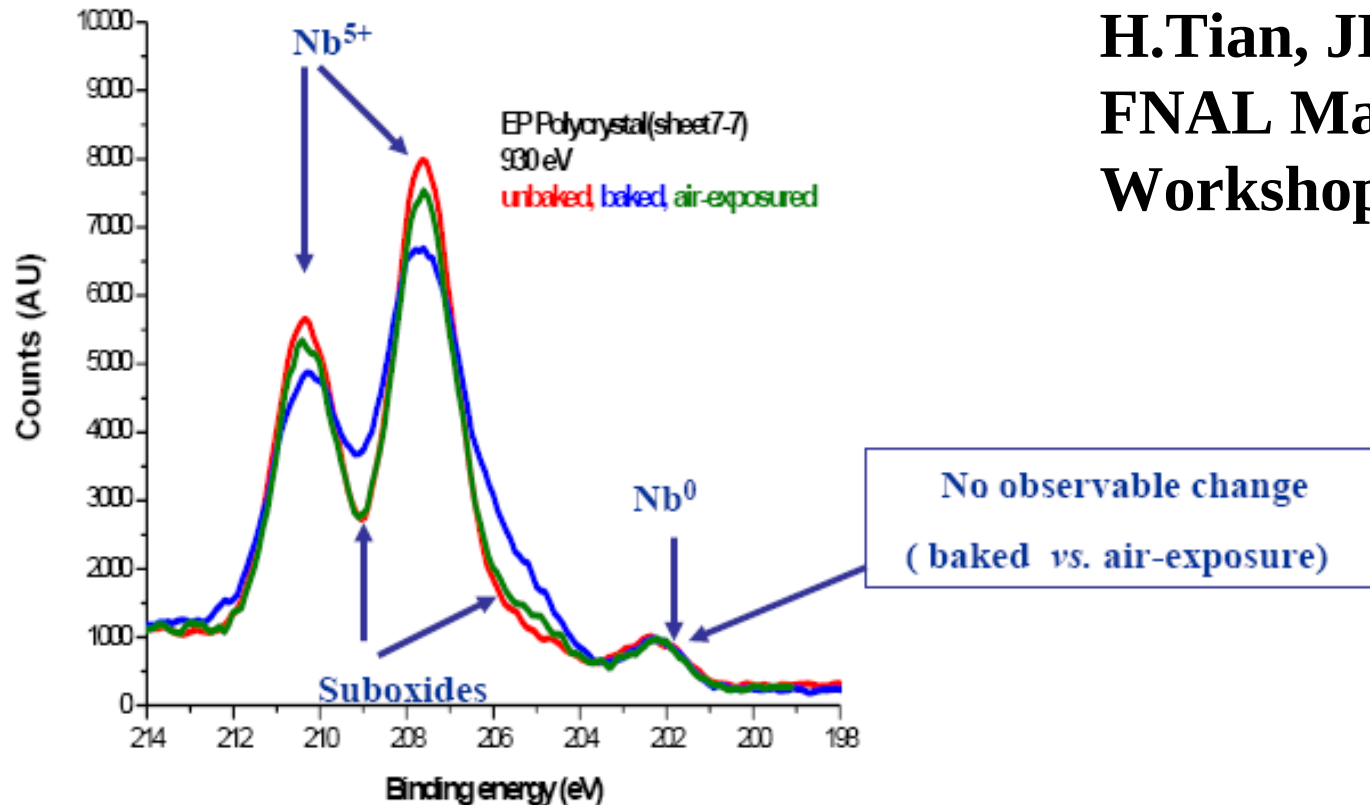


Kowalski et al., SRF'01

- Al K α $h\nu=1486.6$ eV
- Systematic study of mild baking effect on niobium oxide structure
- BUT only “in situ” – no air exposure
- Nb₂O₅ gets partially converted to suboxides – possible cause of residual losses increase (up a few nOhms)



Classic recipe : 120 ° C , 48 hrs, UHV



H.Tian, JLab,
FNAL Material
Workshop, 2007

- Air exposure = back to unbaked – oxide and interface are not responsible



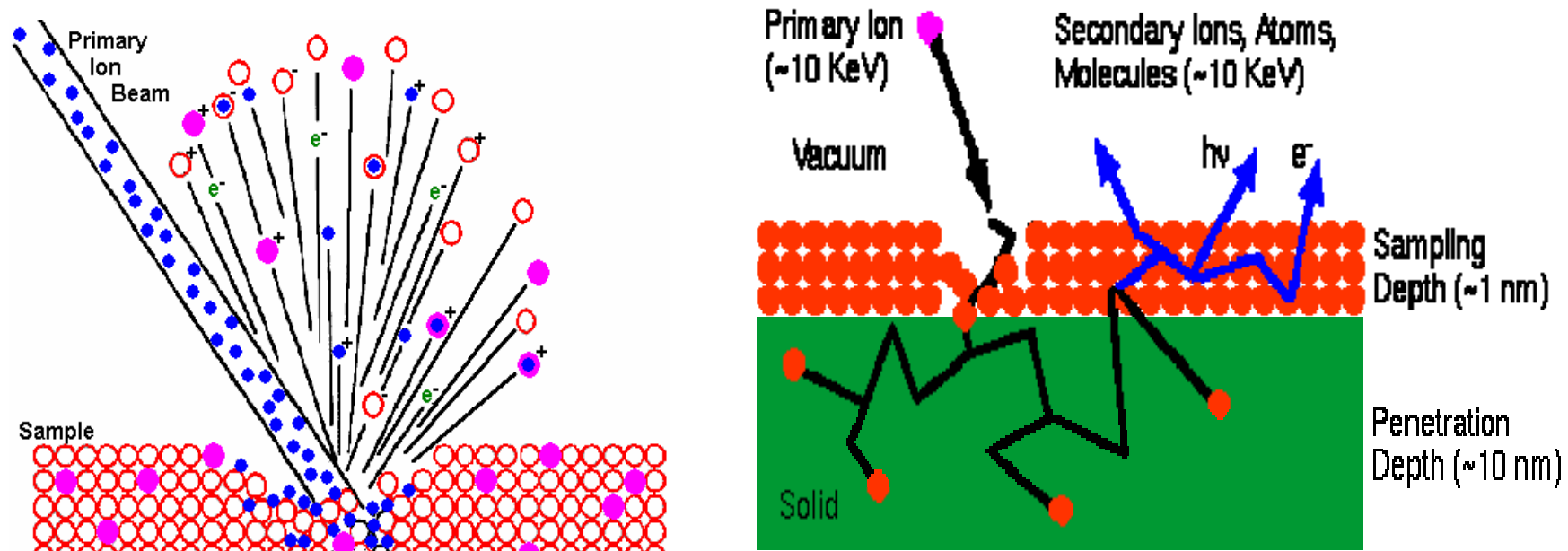
- Oxide structure = mostly Nb_2O_5 + small amount of suboxides
- Mild baking = $\text{Nb}_2\text{O}_5 \rightarrow$ suboxides + slight breakup
- Air exposure after baking = oxide structure back to before baking
- Oxide modification is not responsible for HF Q-slope



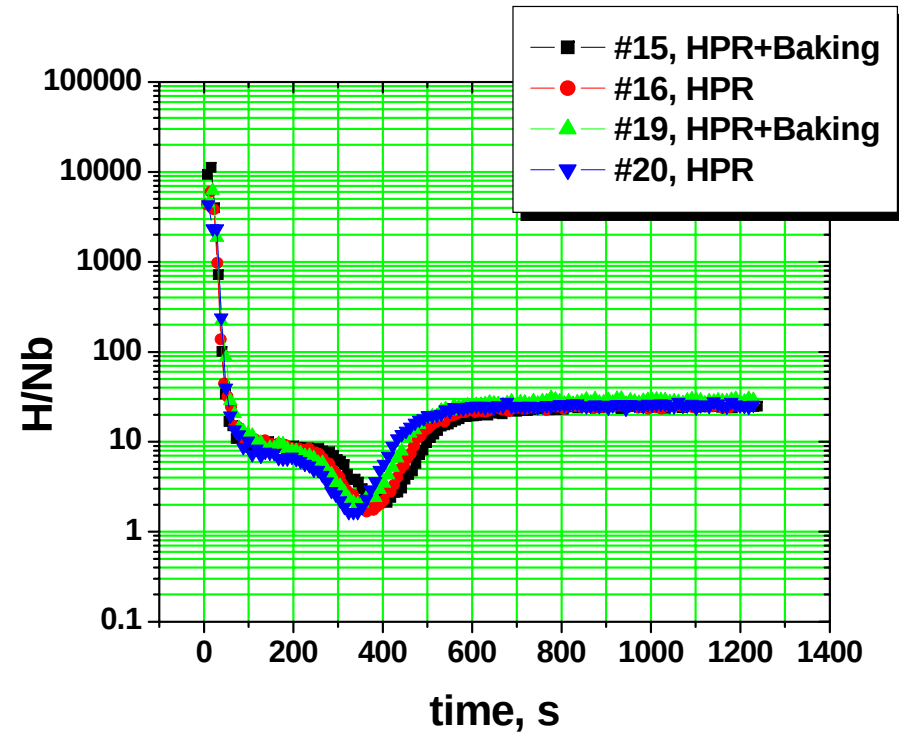
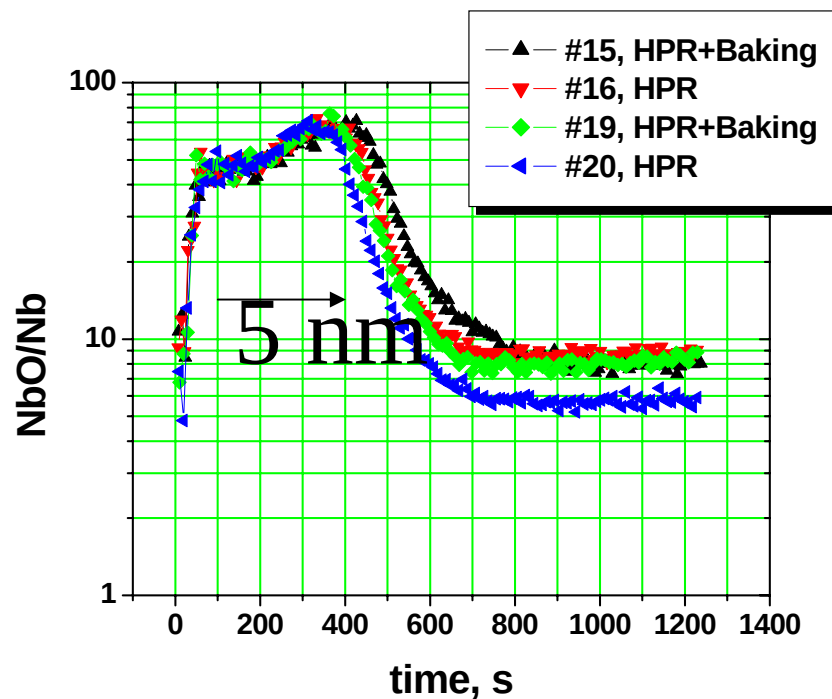
Is it interstitial impurities (O, H,...)?



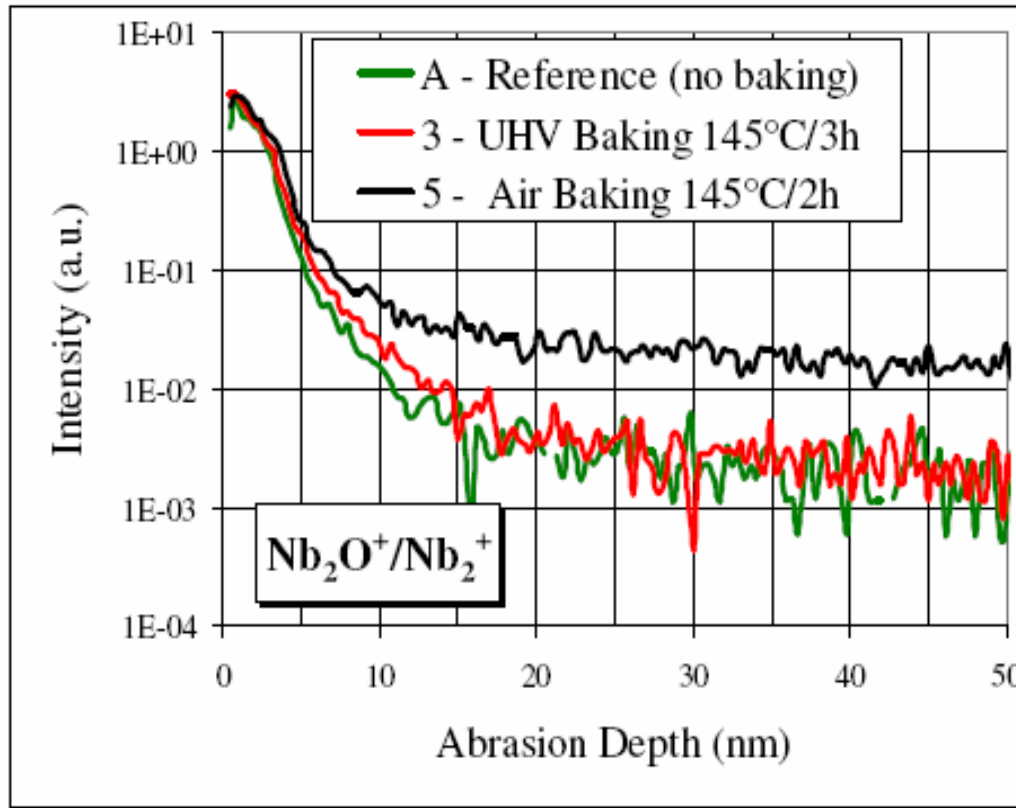
Secondary Ion Mass Spectrometry



- Very sensitive – ppb detection possible
 - Destructive depth profiling
- BUT**
- Instrumental effects – preferential sputtering of oxygen, roughness effect on signal, chemical information not reliable due to sputtering-induced ion production



- Single grain BCP samples
- HPR + 110C 48hrs UHV baking + air exposure
- Spot to spot variation comparable to bake/unbake
- O and H profiles unchanged due to bake

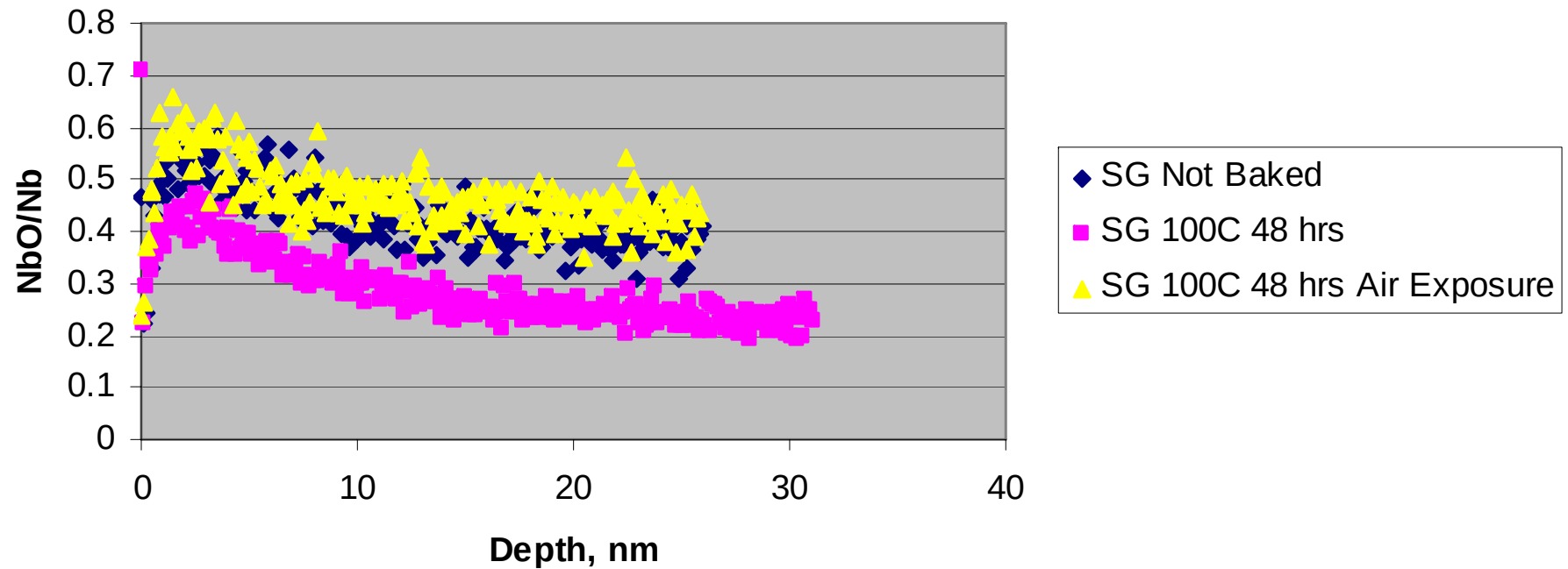


**B. Visentin,
Thin Film
Workshop, 2006**

- Oxygen diffusion is not responsible for mild baking improvement
- But responsible for degradation after higher T baking



Mild baking + Air exposure



Single grain BCP

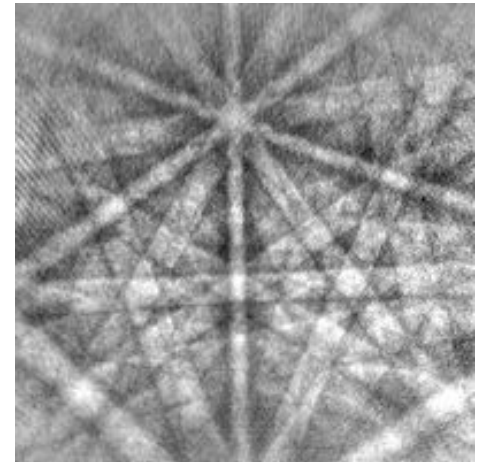
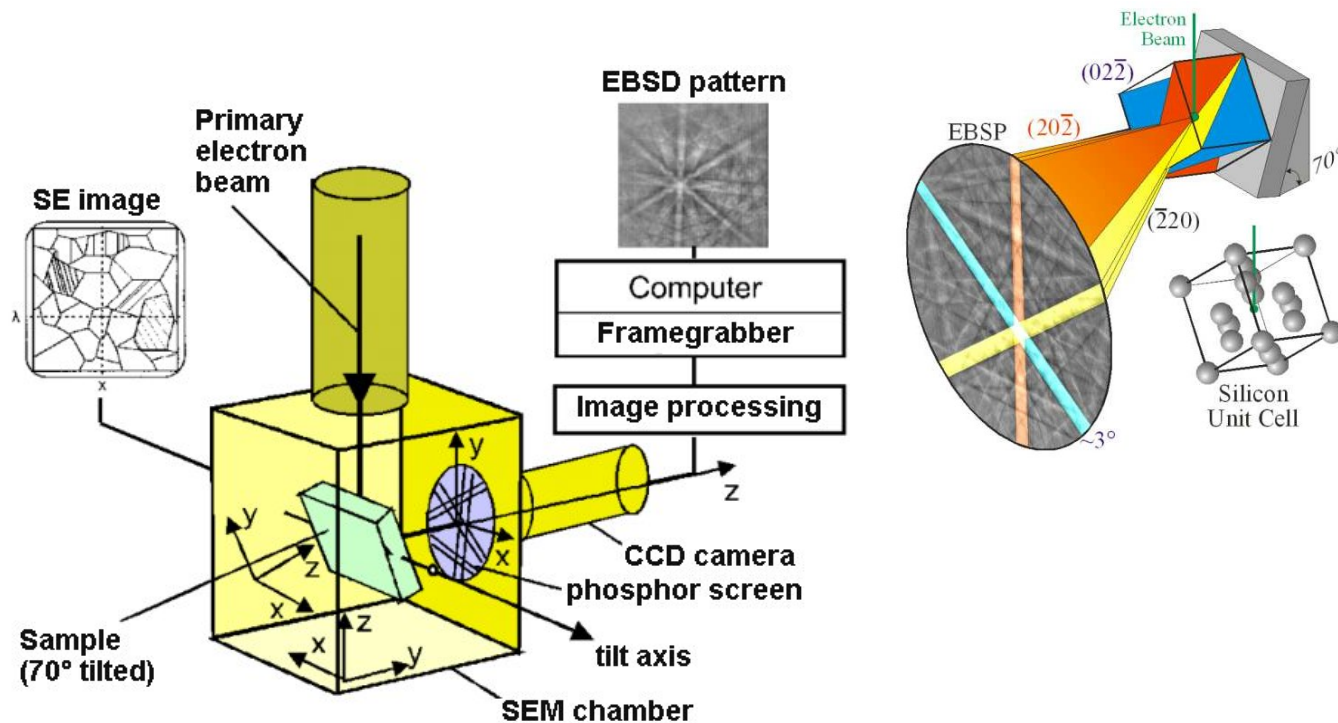
J.Kaufman, Cornell



- No conclusive evidence that oxygen-(impurity-) enriched layer underneath the oxide is responsible for HF Q-slope
- Insignificant change in O related signals after mild baking
 - As opposed to significant effect on cavity performance
- Changes in surface O, NbO, ... due to baking eliminated by air exposure
 - As opposed to cavity performance, which stays same after air exposure



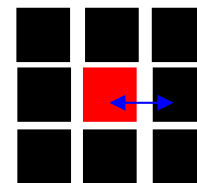
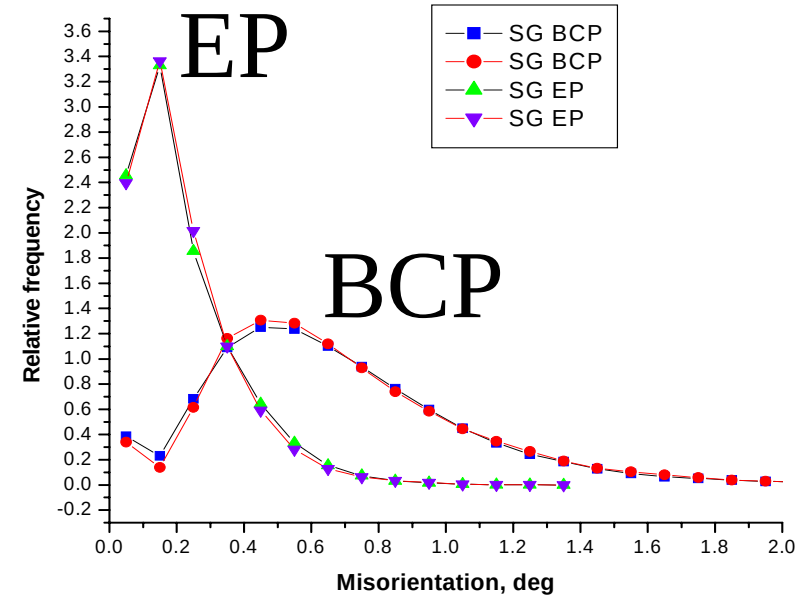
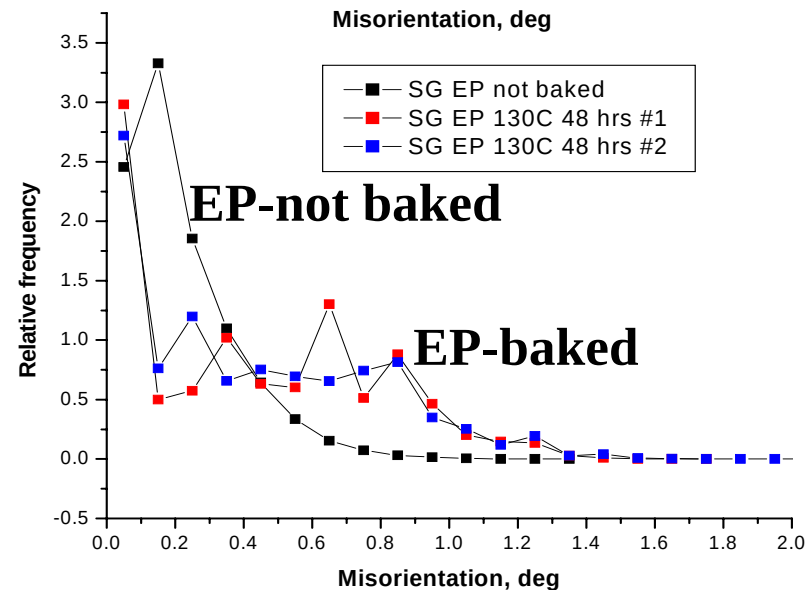
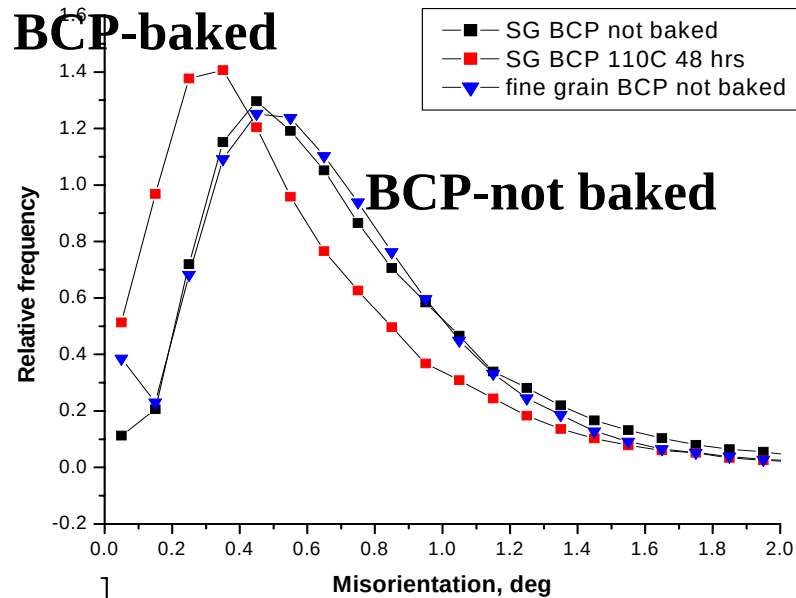
Is it crystalline microstructure?



- Based on diffraction of backscattered electrons
- Information depth – 20-100 nm
- Crystallographic orientation mapping
- Information on crystal defects distribution



EBSD: Local Misorientation



$\Delta\alpha_i$ – angle to rotate the unit cell
to make orientations equal

$$\text{Local misorientation} = 1/8 * \Sigma(\Delta\alpha_i)$$

Baking effect is seen



Roughness role?



AFM: Roughness is the major difference between EP and BCP

BCP

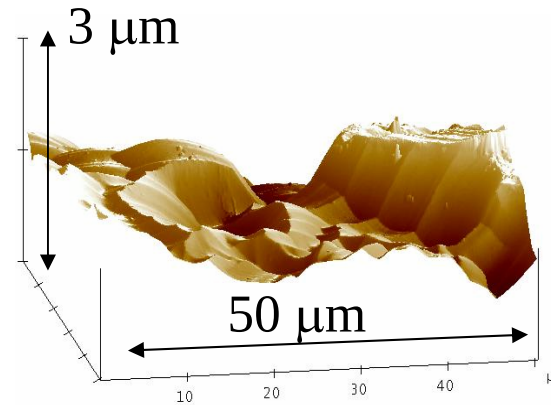
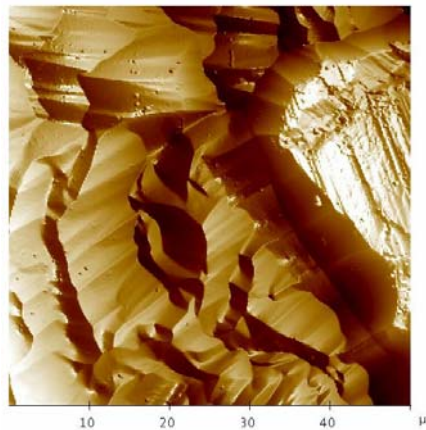


Image Statistics

Img. Z range	2.681 μm
Img. Mean	0.077 nm
Img. Raw mean	-243.23 nm
Img. Rms (Rq)	447.55 nm
Img. Ra	371.30 nm
Img. Rmax	2.608 μm
Img. Srf. area	2526.5 μm^2
Img. Prj. Srf. area	2500.0 μm^2
Img. Srf. area diff	1.061 %
Img. SAE	1.005

EP

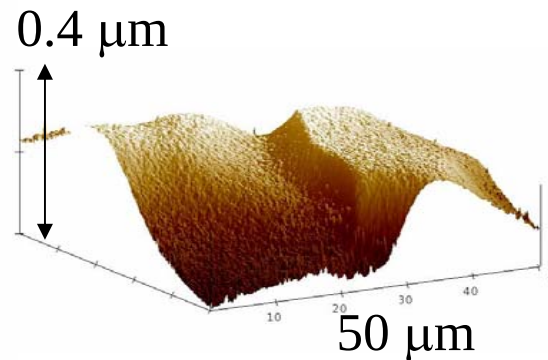
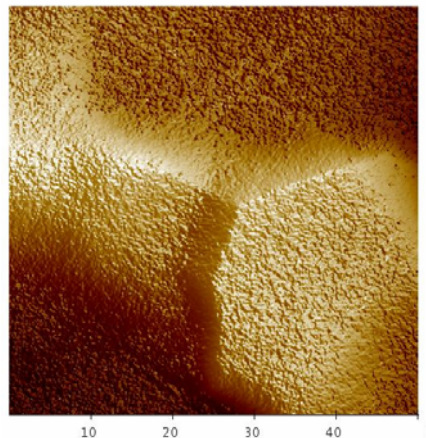


Image Statistics

Img. Z range	349.61 nm
Img. Mean	0.121 nm
Img. Raw mean	-344.43 nm
Img. Rms (Rq)	78.660 nm
Img. Ra	67.523 nm
Img. Rmax	345.21 nm
Img. Srf. area	2501.3 μm^2
Img. Prj. Srf. area	2500.0 μm^2
Img. Srf. area diff	0.051 %
Img. SAE	1.000

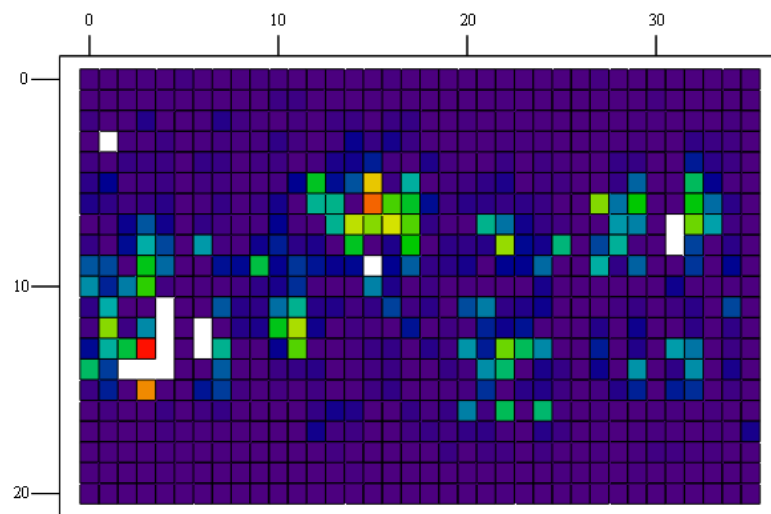
EP - “smoother”, rounded GB steps



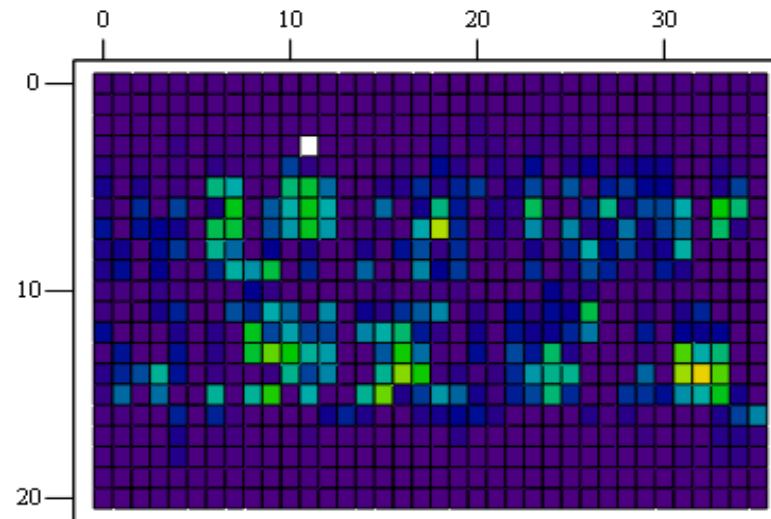
- Oxide not responsible
- Interstitial O not responsible
- Roughness is not a cause of the Q-slope
 - Because EP and BCP have similar Q-slopes before baking
 - But it might contribute to full explanation of why EP is better than BCP after baking
- B_{c3} changes due to mild baking
- Crystalline defect structure may play a role



What causes non-uniformity of heating in the high field Q-slope regime?



Large Grain



Small Grain

T_map

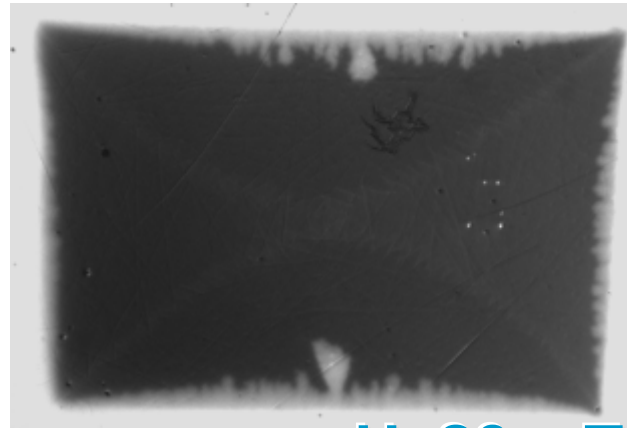
a



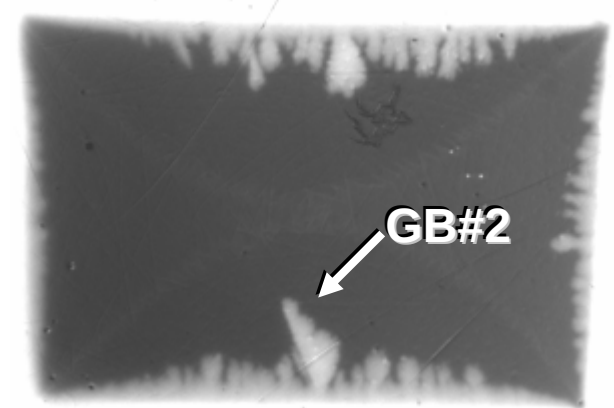
Magneto-Optical Imaging (FSU/ASU – Polianskiy et al.)



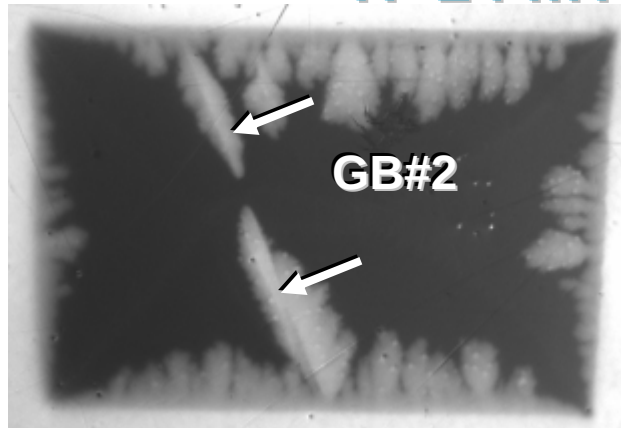
H=24 mT



H=26 mT

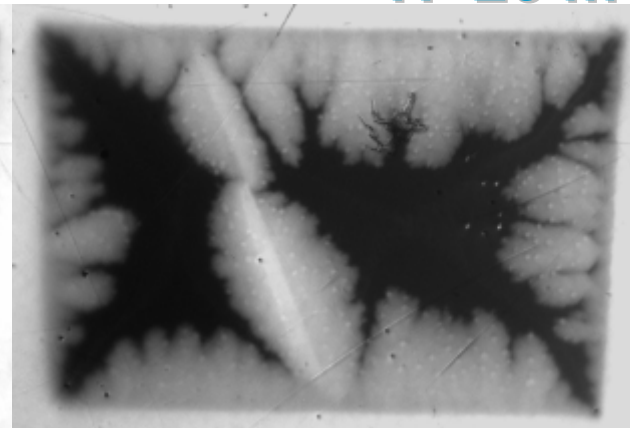


H=28 mT



GB#2

H=32 mT



H=40 mT

Is it GBs?
DC - yes

T=6 K

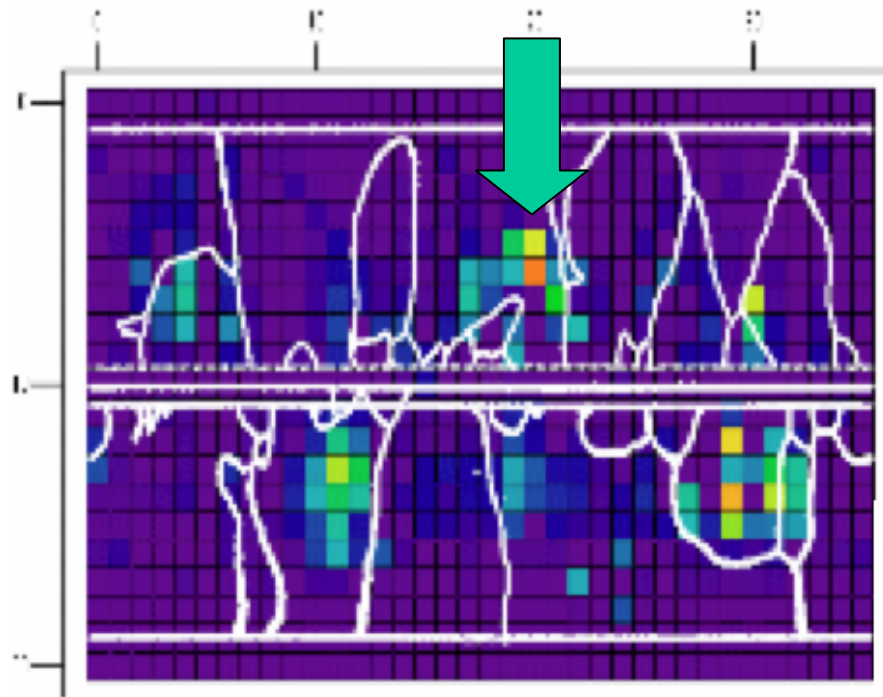
1 mm



DC Magnetic flux penetrates
when magnetic field is parallel to plane of GB).



No heating at GBs (G.Eremeev, Cornell)



Large Grain Cavity

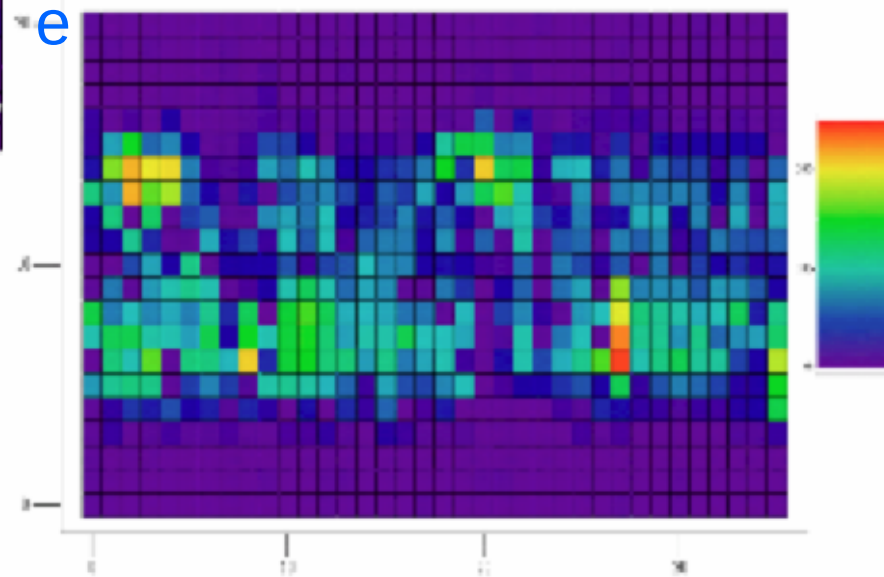
Red = 800 mK

- Grain boundaries are not the regions where stronger heating takes place

RF - No!

Fine-Grain Cavity

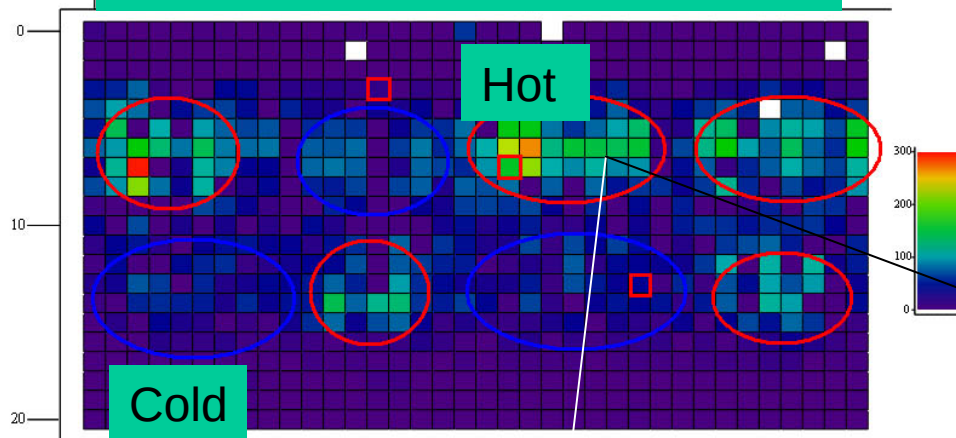
Red = 250 mK



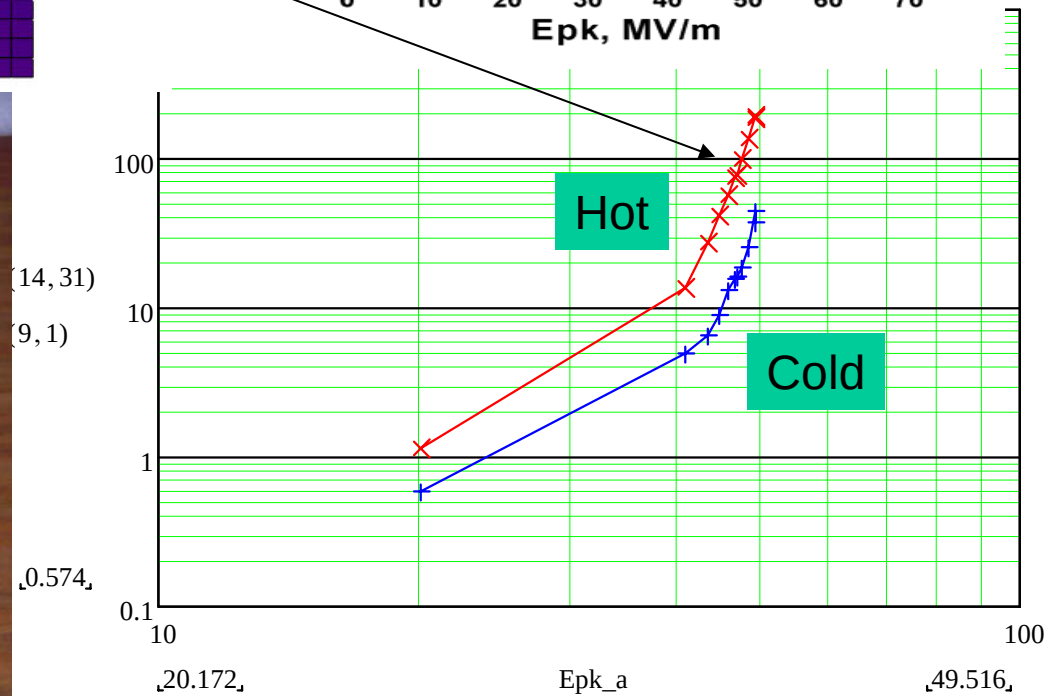
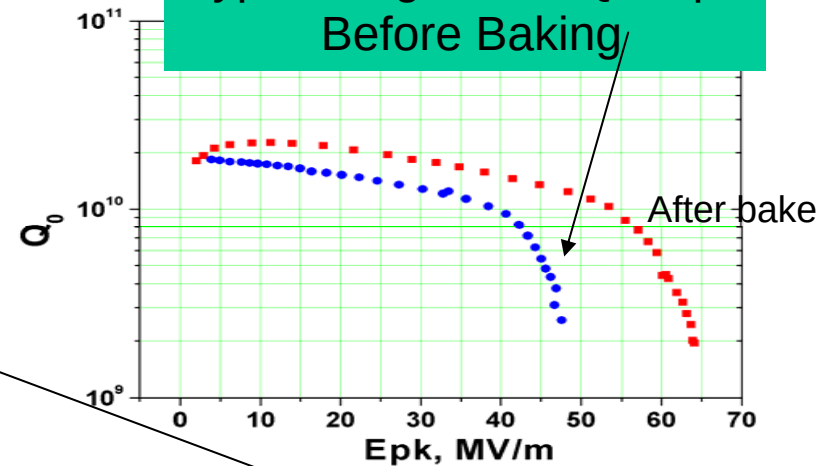


Cornell: Cavity Dissection

Typical Temp Map in the Q-slope
Regime Before Baking

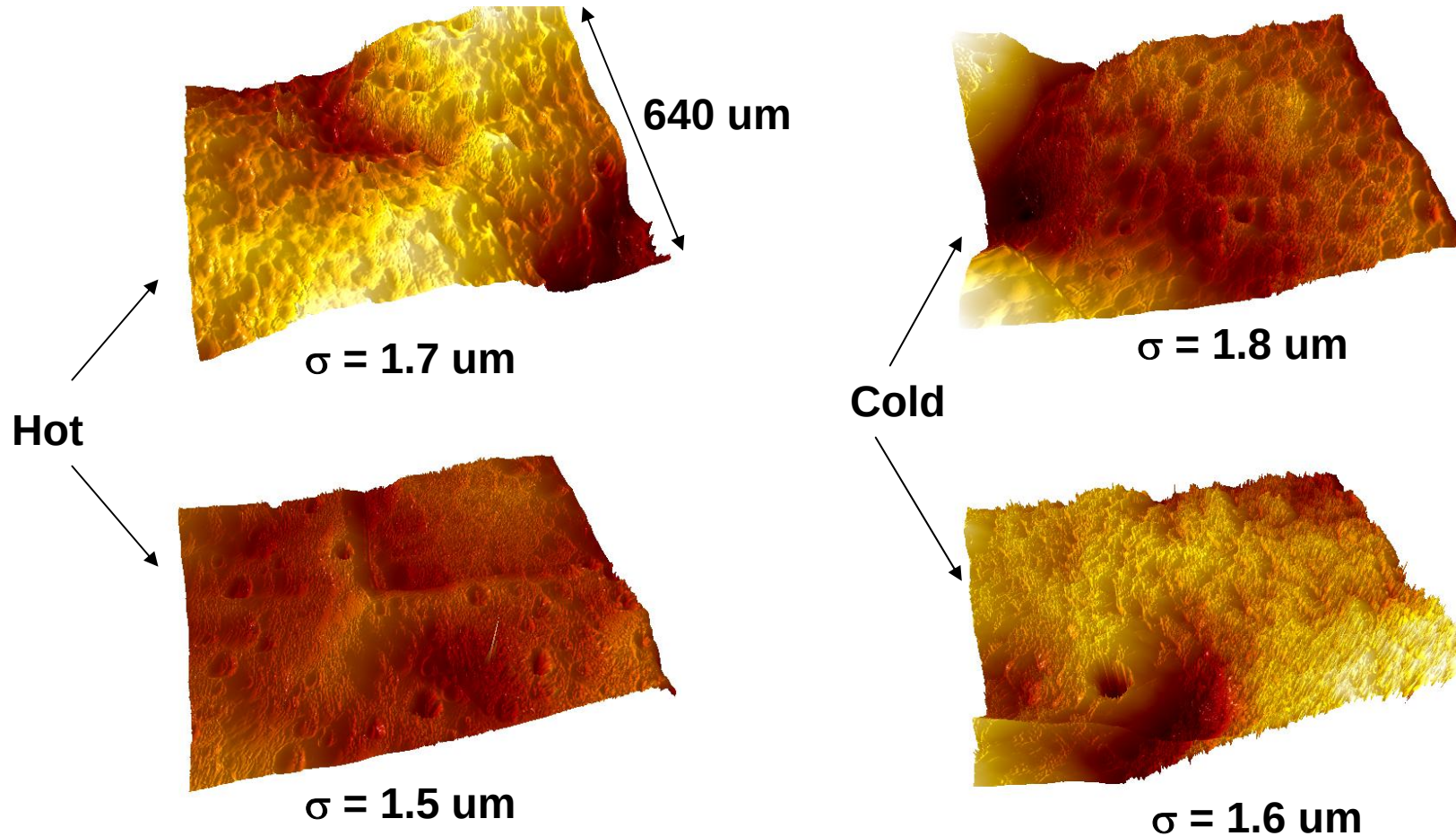


Typical High Field Q-slope
Before Baking





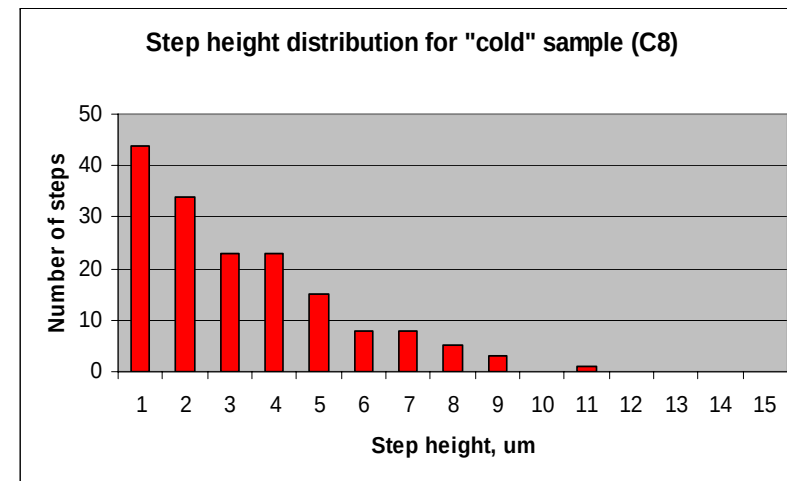
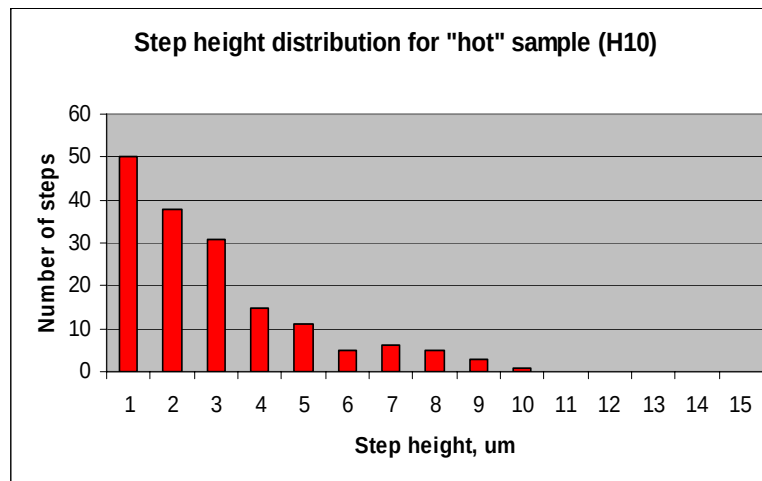
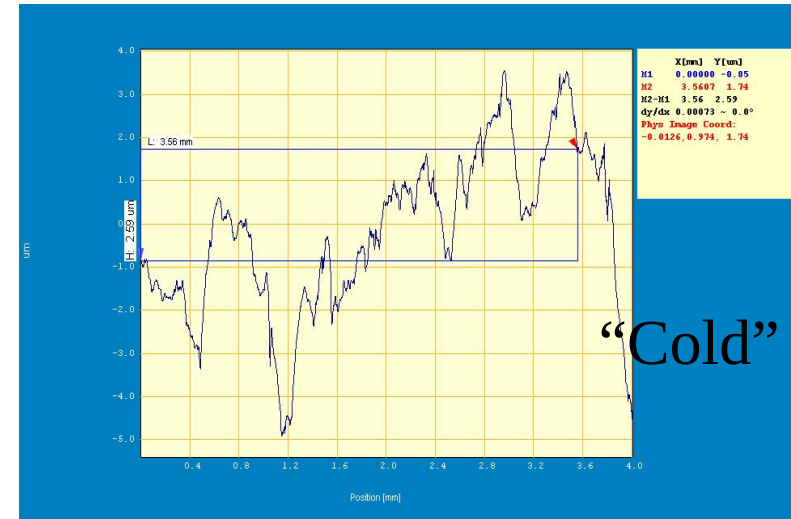
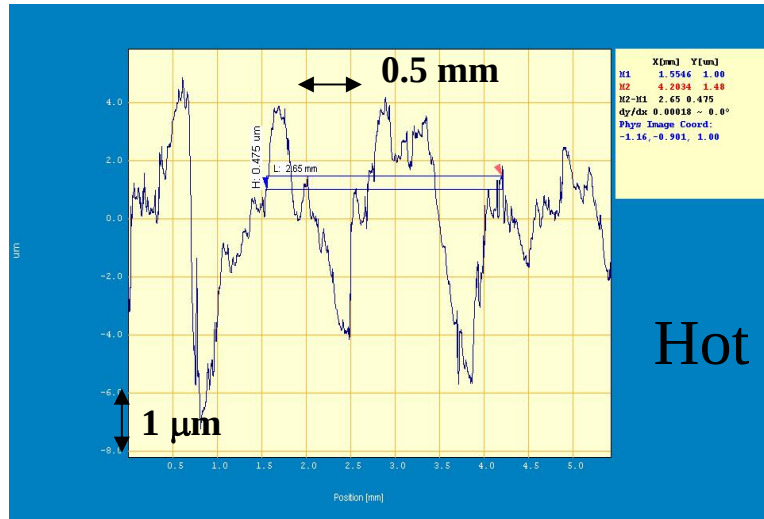
Is non-uniformity caused by roughness variations? – No!

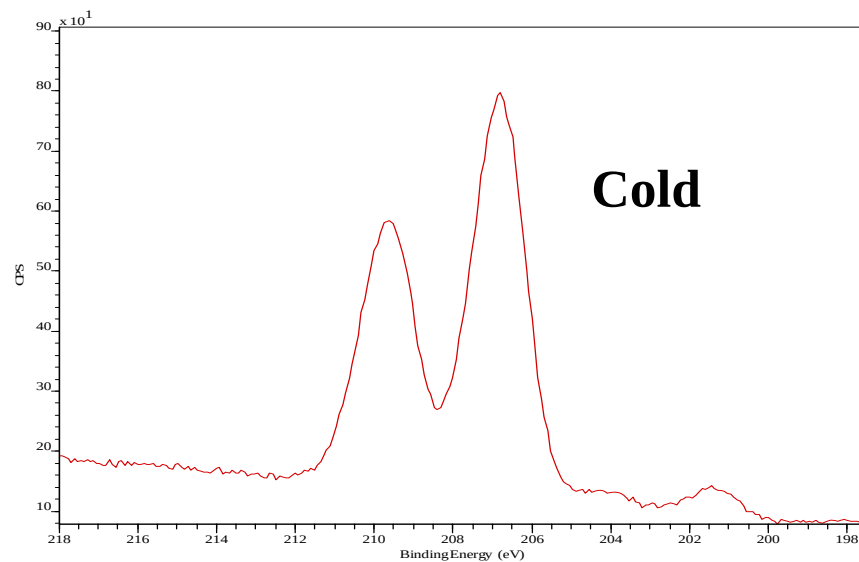
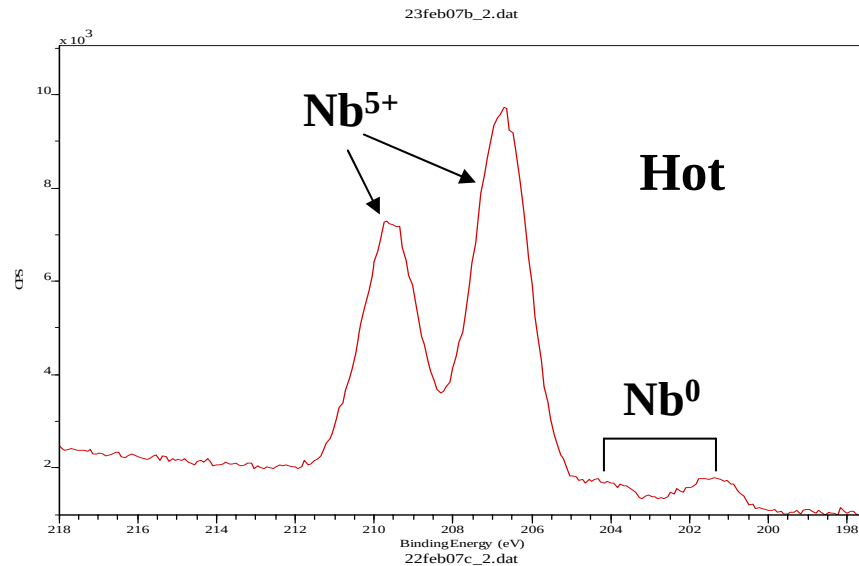


- Average roughness – $\sigma = 1.5\text{-}1.8 \mu\text{m}$ is the same



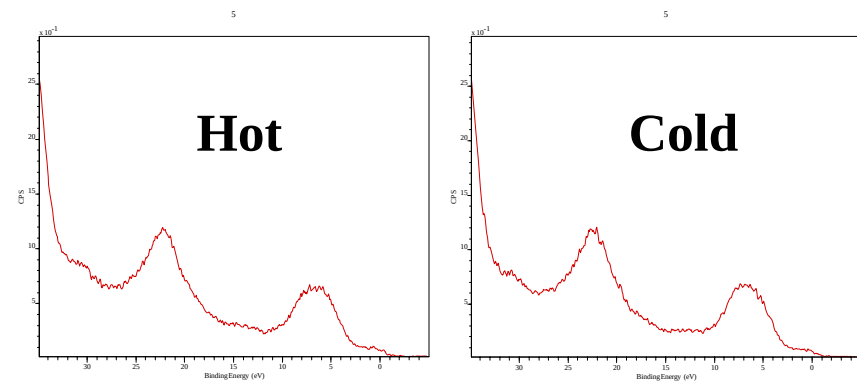
OP: No difference in step heights





- Is patchiness caused by oxide structure differences? – No!

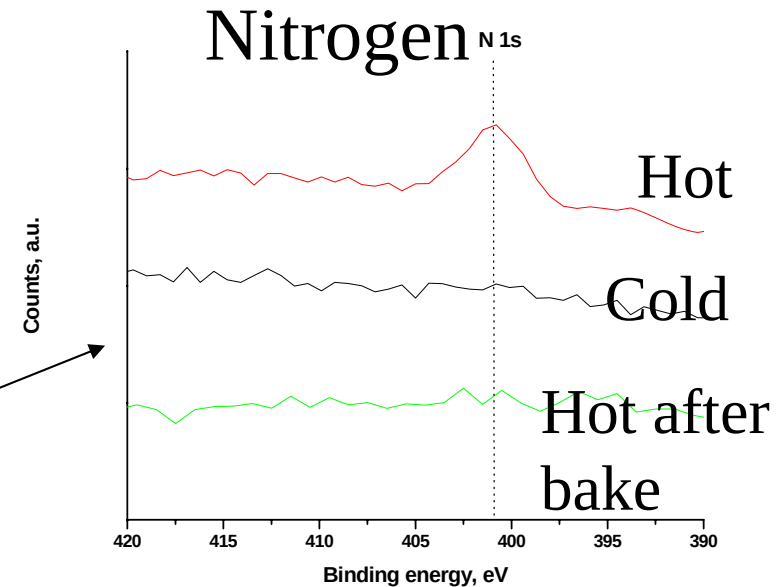
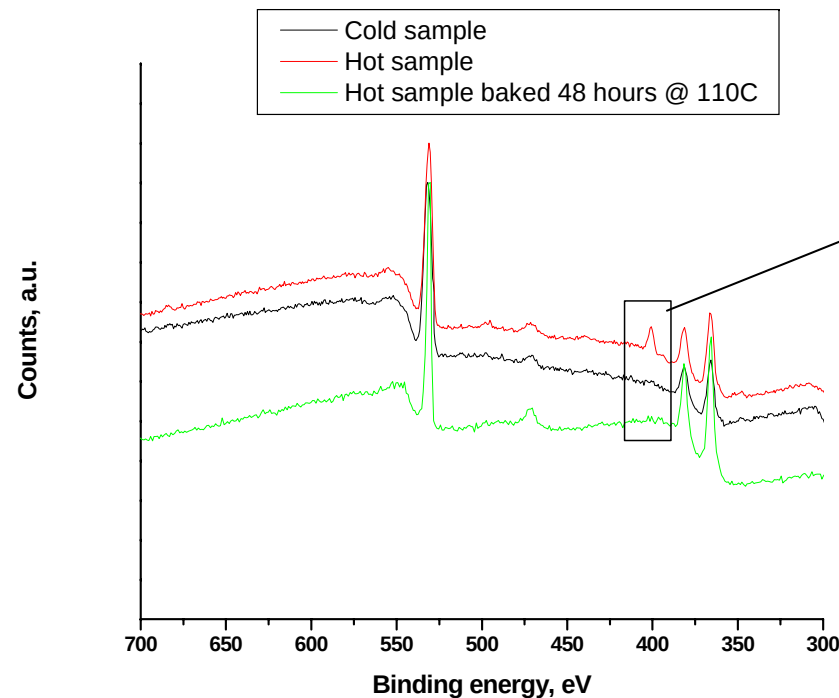
Valence band





Is non-uniformity caused by contaminants other than O?

- Al K α 1486.6 eV X-ray source
- Information depth ~ 7 nm
- 0.5-1 mm grain size

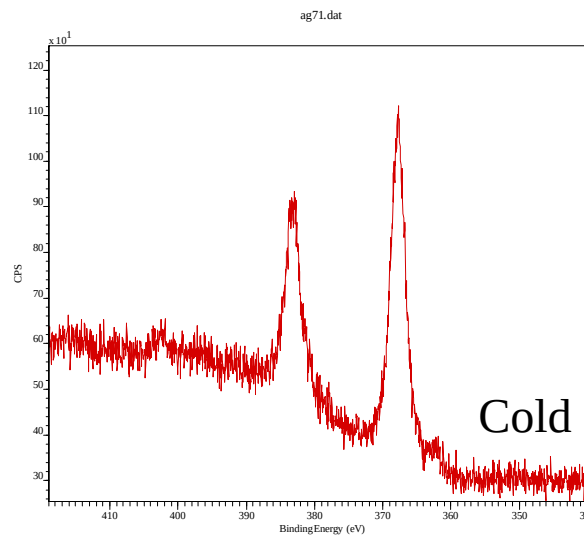
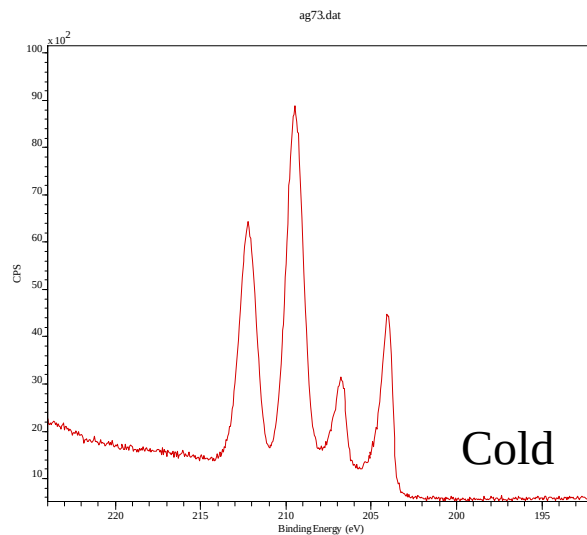
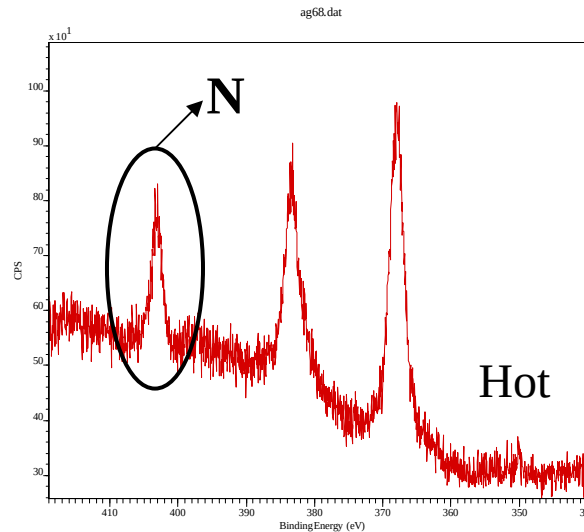
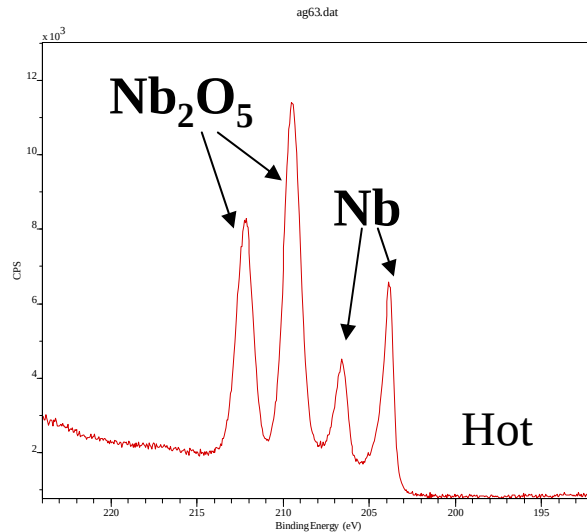


May be:

- Three hottest samples showed nitrogen
- Baking reduced nitrogen



XPS: “Hot” and “Cold” Spots

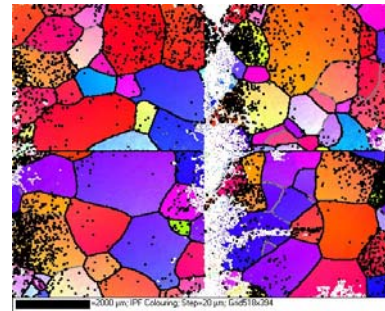
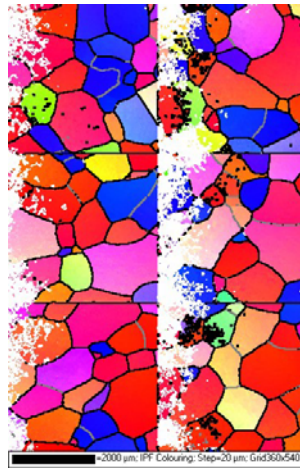
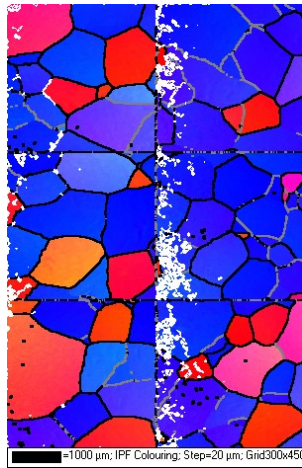
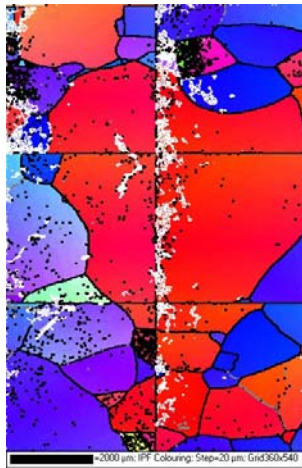


- Synchrotron X-ray source - NSLS
- $h\nu = 2139 \text{ eV}$
- Information depth $\sim 10 \text{ nm}$

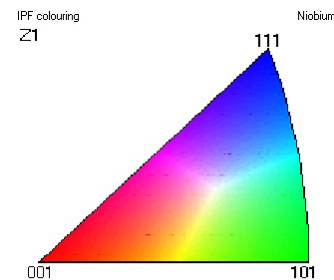
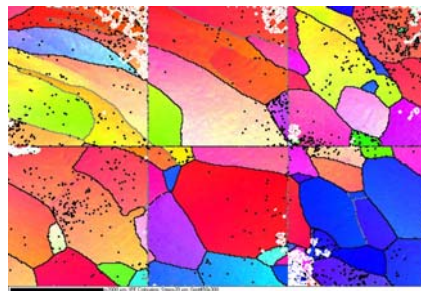
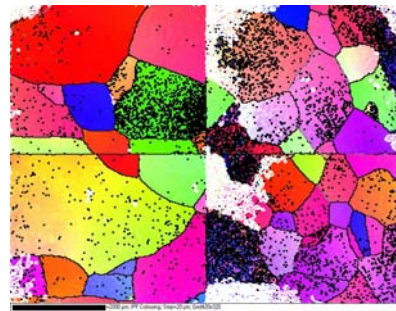
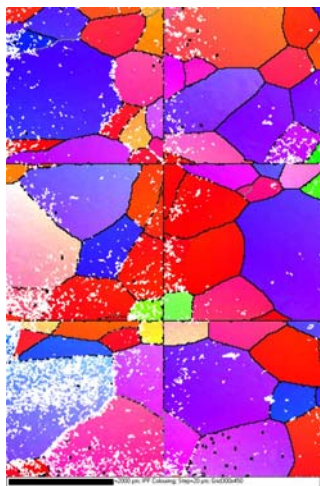
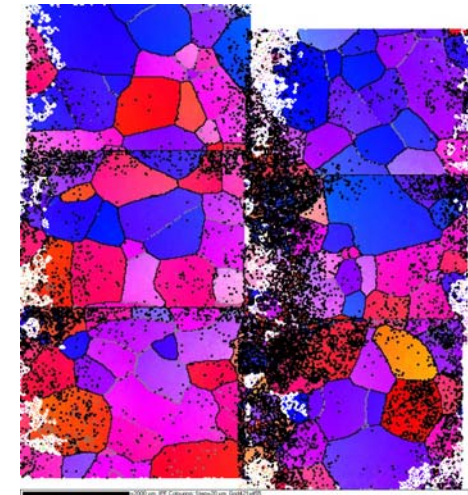
**A. Romanenko
(Cornell),
J. Woicik (NSLS)**



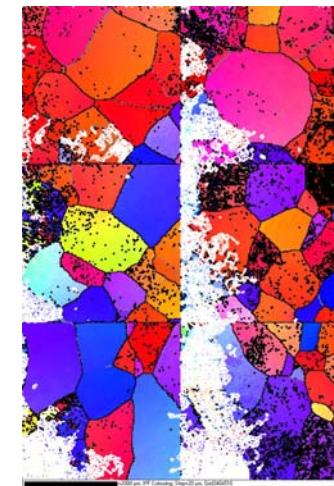
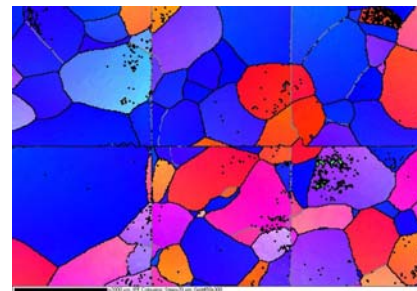
EBSD: Is grain orientation responsible? (Small grain BCP cavity)



Hot

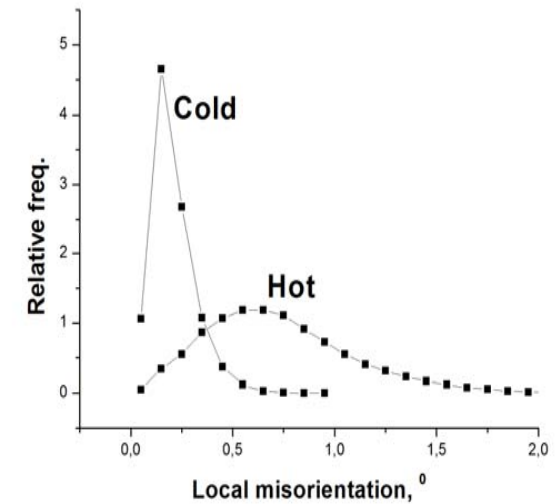
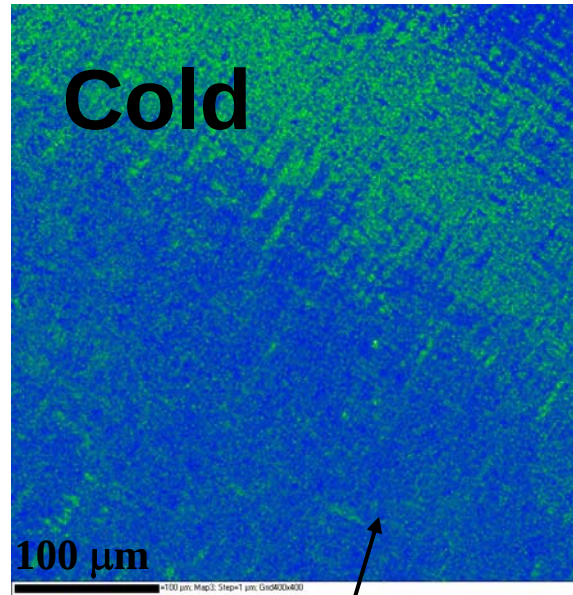
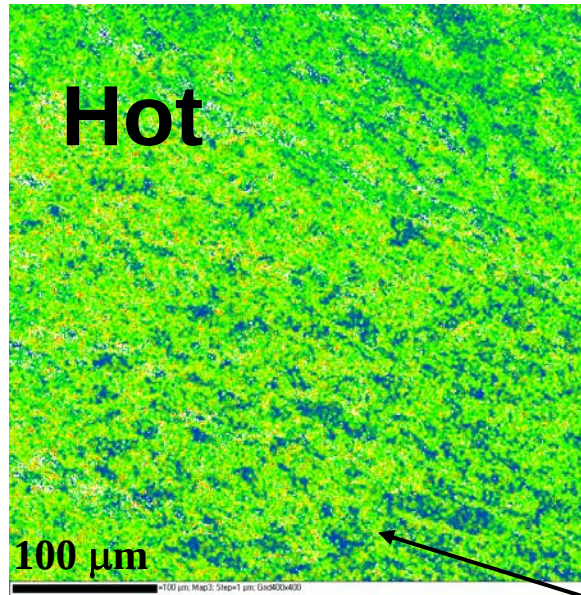


Cold



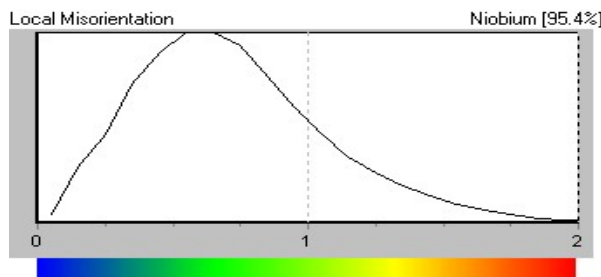


EBSD: Is it crystalline microstructure?



Significant difference!

- Crystalline microstructure is different
 - Different defect (vacancies, dislocations) density

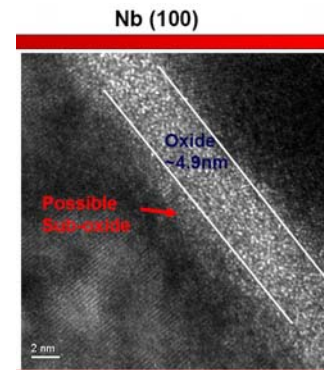




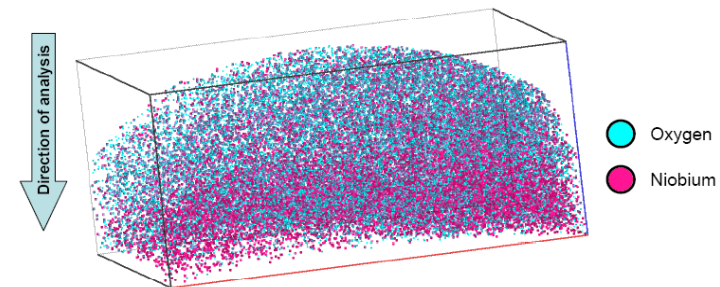
- Contaminants other than O?
 - Nitrogen found in small grain BCP cavity “hot” regions
- Crystalline defects, strain?
 - Difference observed between hot and cold regions in large grain BCP cavity



- TEM (Russell, ...)



- 3DAP (Yoon, ...)



- X-ray techniques (Delheusy, Antoine)
 - Diffuse diffraction, crystal truncation rod, reflectometry



- SIMS, XPS do not support O related pollution layer or its change due to baking
- Grain boundaries – no contribution observed
- Preferred crystalline orientation – not a cause
- Roughness is not playing a primary role but may be subsidiary
- Crystalline defect structure within penetration depth might play a role
 - Different in BCP and EP
 - Sensitive to mild baking
 - Preliminary - different in “hot” and “cold” spots
 - More studies needed